

**Search Notes**

Application/Control No.

10/658,275

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

HICKEY ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12	7/31/2006	DWY
429	30	7/31/2006	DWY
429	46	7/31/2006	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
429	12	7/31/2006	DWY
429	30	7/31/2006	DWY
429	46	7/31/2006	DWY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/31/2006	DWY
Inventorship Search	7/31/2006	DWY